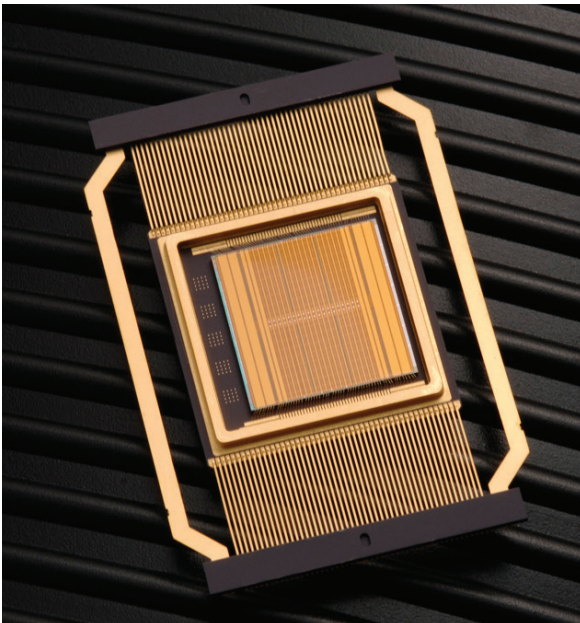


# Monolithic 16M radiation-hardened SRAM



## High-speed memory product

The monolithic 16 Mb static random access memory is BAE Systems' next-generation, radiation-hardened memory product for users in the space community.

## Description

Capable of withstanding the effects of natural space and an upper radiation-hardened environment, the 16 Mb monolithic SRAM has total-dose tolerance of greater than 1 Mrad and an upset rate of less than  $1\text{E-}12$  upsets per bit-day. Prompt dose levels are  $>1\text{E}9$  rad/sec.

## Key features

- Read and write access time 13.5 ns typical, 17 ns and 20 ns worst case
- Operating temperature range -55 degrees Celsius to +125 degrees Celsius
- Operating voltage (core) 1.5V
- Operating voltage (I/O) 3.3V
- Standby power < 2 mW typical, < 100 mW worst case
- Operating power < 7.5 mW/MHz typical
- Packaging 86-lead ceramic flatpack
- Asynchronous operation
- Prototype and flight flows
- Latchup-immune

## System definitions

**A:0-20** Address input pins that select a particular 8-bit word within the memory array.

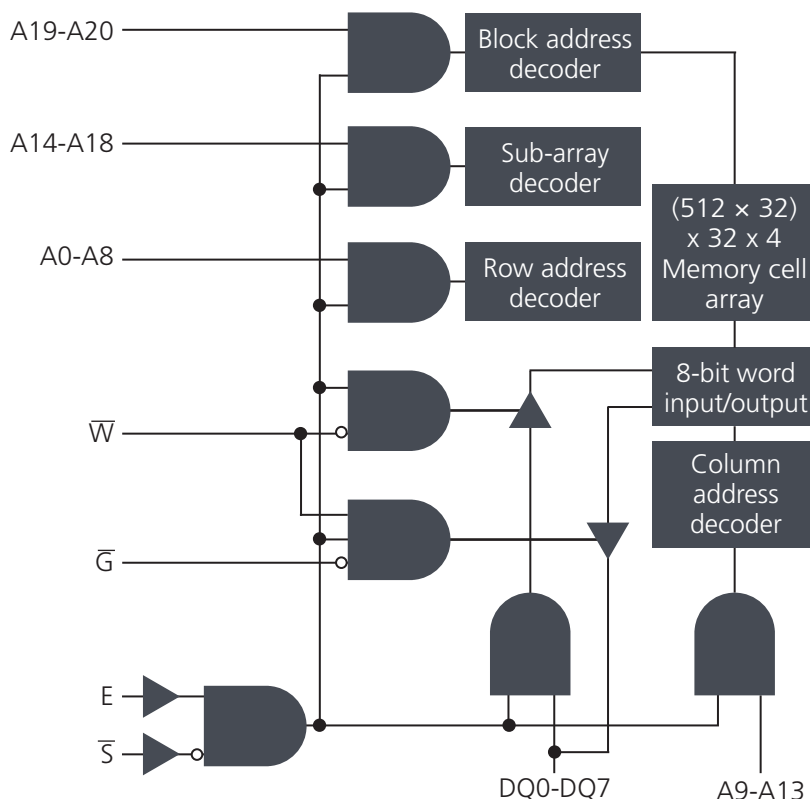
**DQ:0-7** Bi-directional data pins that serve as data outputs during a read operation and as data inputs during a write operation.

$\overline{S}$  Negative chip select at a low level allows normal read or write operation. At a high level,  $\overline{S}$  forces the SRAM to a precharge condition, holds the data output drivers in a high-impedance state, and disables only the data input buffers. If this signal is not used, it must be connected to GND.

$\overline{W}$  Negative write enable at a low level activates a write operation and holds the data output drivers in a high-impedance state. At a high-level  $\overline{W}$  allows normal read operation.

$\overline{G}$  Negative output enable at a high level holds the data output drivers in a high-impedance state. At a low level, the data output driver state is defined by  $\overline{S}$ ,  $\overline{W}$ , and E. If this signal is not used, it must be connected to GND.

**E** Chip enable at a high level allows normal operation. At a low level, E forces the SRAM to a precharge condition, holds the data output drivers in a high-impedance state, and disables all the input buffers except the  $\overline{S}$  input buffer. If this signal is not used, it must be connected to VDD.



## Specifications

Monolithic 16 Mb family of products

16 Mb SRAM single chip die are organized in either a 2M x 8 or 512K x 32 format, packaged in an 86-lead ceramic flatpack

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